

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants : Hideaki KAWAMURA et al.

Group Art Unit : Not Yet Assigned

Appl. No. : 10/509,678 ✓  
(U.S. National Stage of PCT/JP03/5557)

Examiner : Not Yet Assigned

I.A. Filed : April 30, 2003

For : PICTURE ANGLE DETECTION APPARATUS AND SCANNING  
LINE INTERPOLATION DEVICE HAVING THE SAME

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents  
U.S. Patent and Trademark Office  
220 20th Street S.  
Customer Window, Mail Stop AMENDMENT  
Crystal Plaza Two, Lobby, Room 1B03  
Arlington, VA 22202

Sir :

In accordance with the duty of disclosure under 37 C.F.R. §1.56 and §§1.97-1.98, Applicants hereby submit a copy of an International Search Report that was mailed on August 12, 2003, with respect to International Patent Application No. PCT/JP03/5557, of which the present application is the U.S. National Stage Application, in which the following documents were cited:

Japanese Laid-Open Patent Publication No. HEI 11-146346, together with an English language Abstract and partial English language translation of the same;

Japanese Laid-Open Patent Publication No. 2000-253238, together with an English language Abstract and partial English language translation of the same;

Japanese Laid-Open Patent Publication No. 2003-52023, together with patent family member International Application No. WO 02/48965 and U.S. Patent Application Publication No. 2003/0011708;

Japanese Laid-Open Patent Publication No. HEI 5-153562, together with patent family member U.S. Patent No. 5,347,599;

Japanese Laid-Open Patent Publication No. HEI 11-41565, together with an English language Abstract of the same; and

Japanese Laid-Open Patent Publication No. HEI 11-331773, together with an English language Abstract of the same.

The category of relevance, pertinent portions, and claims to which each document is relevant, as ascertained by the Japanese Examiner are set forth in the International Search Report.

Applicants also bring to the Examiner's attention the following documents:

Japanese Laid-Open Patent Publication No. HEI 9-37214, together with patent family members U.S. Patent No. 5,886,745 and U.S. Patent No. 5,796,437. Applicants note that the Japanese patent document is cited on page 2 of the specification of the present application; and

Japanese Laid-Open Patent Publication No. HEI 2-213289, together with an English language Abstract of the same.

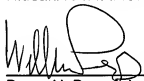
Further to 37 C.F.R. §1.98 (a)(2)(ii), copies of the U.S. patents and U.S. patent application publication are not enclosed herewith. However, if any copies are needed, the Examiner is respectfully requested to contact the undersigned.

Applicants respectfully request that the Examiner consider the above material and cite the same. Copies of the above-noted foreign documents are attached hereto and all of the documents are listed on the attached PTO-1449 Form. The Examiner is requested to initial the appropriate spaces on the attached Form and to return a copy of the completed Form to Applicants with the next official communication in the present application.

Applicants note that an Office Action on the merits has not issued in the present application, and thus no fee is believed necessary to ensure consideration of the submitted material.

Should the Examiner have any questions, the Examiner is invited to contact the undersigned at the below-listed telephone number.

Respectfully Submitted,  
Hideaki KAWAMURA et al.

  
Bruce H. Bernstein  
Reg. No. 29,027

William Pieprz  
Reg. No. 33,630

William Pieprz  
Reg. No. 33,630

January 10, 2005  
GREENBLUM & BERNSTEIN, P.L.C.  
1950 Roland Clarke Place  
Reston, VA 20191  
(703) 716-1191

FORM PTO-1449

U.S. Department of Commerce  
Patent and Trademark OfficeAtty. Docket No.  
P26093Application No.  
10/509,678INFORMATION DISCLOSURE STATEMENT  
BY APPLICANT  
(Use several sheets if necessary)Applicant  
Hideaki KAWAMURA et al.Filing Date  
I.A. Filed April 30, 2003Group  
Not Yet Assigned

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
N.K./	2003 /	0 0 1 1 7 0 8	01/16/03	KAWAMURA et al.			
N.K./		5 3 4 7 5 9 9	09/13/94	YAMASHITA et al.			
N.K./		5 8 8 6 7 4 5	03/23/99	MURAJI et al.			
N.K./		5 7 9 6 4 3 7	08/18/98	MURAJI et al.			

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES	NO
N.K./	11	- 1 4 6 3 4 6	05/28/99	JAPAN			X	
N.K./	2000	- 2 5 3 2 3 8	09/14/00	JAPAN			X	
N.K./	2003	- 0 5 2 0 2 3	02/21/03	JAPAN				
N.K./	0	2 / 4 8 9 6 5	06/20/02	W.I.P.O.				
N.K./	5	- 1 5 3 5 6 2	06/18/93	JAPAN				
N.K./	11	- 0 4 1 5 6 5	02/12/99	JAPAN				
N.K./	11	- 3 3 1 7 7 3	11/30/99	JAPAN				
N.K./		9 - 3 7 2 1 4	02/07/97	JAPAN				
N.K./	2	- 2 1 3 2 8 9	08/24/90	JAPAN				

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

N.K./		1	English Language Abstract of JP 11-146346.
N.K./		2	English Language Abstract of JP 2000-253238.
N.K./		3	English Language Abstract of JP 11-041565.
N.K./		4	English Language Abstract of JP 11-331773.
N.K./		5	English Language Abstract of JP 2-213289.

EXAMINER Victor Kostak/

DATE CONSIDERED 06/02/2008

\*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.